Abstracts

Measurement-Based Large-Signal Diode Model, Automated Data Acquisition System, and Verification with On-Wafer Power and Harmonic Measurements

D.E. Root, M. Pirola, S. Fan and A. Cognata. "Measurement-Based Large-Signal Diode Model, Automated Data Acquisition System, and Verification with On-Wafer Power and Harmonic Measurements." 1993 MTT-S International Microwave Symposium Digest 93.1 (1993 Vol. I [MWSYM]): 261-264.

A new relaxation-time large-signal table-based diode model for circuit simulation is presented. Also presented is a fully automated system which characterizes the device and generates the tabular data file used by the model. Excellent agreement between simulated and measured fundamental and second through fourth harmonic power levels is demonstrated for a MODFET diode up to frequencies of 48 GHz.

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